



Approved Method: **Spectroradiometric Measurement Methods for Light Sources**

IES LM-58-13 Approved Method: Spectroradiometric Measurement Methods for Light Sources



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Publication of this Approved
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should be directed to the IES.

Prepared by:
The Sub-Committee on Photometry of Light Sources
of the IES Testing Procedures Committee

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of the IES Testing Procedures Committee**

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